

High-level combined deterministic and pseudo-exhaustive test generation for RISC processors

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Jenihhin, Maksim; Gürsoy, Cemil Cem; Raik, Jaan 2019 IEEE European Test Symposium (ETS) : proceedings 2019 / 6 p. : ill <https://doi.org/10.1109/ETS.2019.8791526>

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Implementation-independent test generation for a large class of faults in RISC processor modules

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